PCN Number: 20		2021	0210511000.1A						PCN Date: May 27, 2021			May 27, 2021	
Title	Title: Qualification of Amkor Korea K4 as an Additional Assembly Location for Select Devices												
Customer Contact:				PCN Manager Dept:				pt:	Quality Serv			ices	
Proposed 1 st Ship Date:				Aug 13, 2021				Estimated San Availability:			npl	Date provided upon request	
	Change Type:												
Assembly Process Data Sheet Wafer Bump Mat													
Assembly Materials Machanical Specification					Part number chan Test Site			er chang	е	<u> </u>		afer Bump Process afer Fab Site	
Mechanical SpecificationPacking/Shipping/Labeli					Test Process			955		H		afer Fab Materials	
	racking	<i>y</i> Smpping	Label	iiig				.55		Ħ		afer Fab Process	
							PCN	N De	etails				<u></u>
Des	cription	n of Chan	ge:										
The 202 for 1	notification. These new devices are highlighted and bolded in the Product affected section below. The expected first shipment date for these new devices will be 90 days from this notice (Aug 27, 2021) for these newly added devices only. The proposed 1 st ship date of Aug 13, 2021 still applies for the original set of devices. Texas Instruments is pleased to announce the qualification of Amkor Korea K4 as an additional Assembly location for the devices listed below. Device construction materials differences are noted in the table below:												
				Sh	inko	<u> </u>			Amkor K	4			
	Stud Bump material Au Bump Cu Pillar Bump												
Underfill Mold compound			U8437-48				101388679						
			CV	CV8710				1013000	101355509				
Rea	son for	Change:		Reason for Change:							_		
Con	Continuity of Supply									09	<u> </u>		
Anticipated impact on Fit, Form, Function, Quality or Reliability (positive / negative):								:		09			
	· ·		on Fit	Forn	1, Fı	un	ction		10135550		ility	(p	ositive / negative):
Ant	icipated		on Fit	, Forn	1, Fı	un	ction		10135550		ility	(p	ositive / negative):
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MSL 1 /235C/UNLIM 03/29/04

(P) (2P) REV: (V) 0033317 (20L) CSO: SHE (21L) CCO: USA (22L) ASO: MLA (23L) ACO: MYS

Product Affected

3530ECUSAGRM	OMAP3515ECBB	OMAP3525ECUS	OMAP3530ECBBLPD
OMAP3503ECBB	OMAP3515ECBBA	OMAP3525ECUSA	OMAP3530ECUS
OMAP3503ECBBA	OMAP3515ECUS	OMAP3530ECBB	OMAP3530ECUS72
OMAP3503ECBBALPD	OMAP3515ECUS72	OMAP3530ECBB72	OMAP3530ECUSA
OMAP3503ECUS	OMAP3515ECUSA	OMAP3530ECBBA	
OMAP3503ECUS72	OMAP3525ECBB	OMAP3530ECBBALPD	
OMAP3503ECUSA	OMAP3525ECBBA	OMAP3530ECBBAR	

Qualification Report

Approve Date 20-May-2021

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

		= ata Biop			C.C. Campio C	ize / Total lanea		
Туре	Test Name / Condition	Duration	Qual Device: DM3730CBC	Qual Device: DM3730CBP	Qual Device: DM3730CUS	Qual Device: OMAP35xxCUS	Qual Device: OMAP35xxCBB	Qual Device: WL1285QAAP
PC	Preconditioning	MSL3 / 260C	3/900/0	1/100/0	1/100/0	-	1/100/0	3/780/0
PC	Preconditioning	MSL4/260C				1/100/0		
SAM	CSAM/TSAM study after Preconditioning	Delamination inspection	3/30/0	1/20/0	1/20/0	1/20/0	1/20/0	3/36/0
THB	Biased Temperature and Humidity 85C/85%RH	1000 hours	3/75/0					
UHAST	Unbiased HAST 110C/85%RH	264 hours	3/75/0					3/231/0
TC	Temperature Cycle, -55/125C	700cyc	3/75/0					3/231/0
HTSL	High Temp Storage Bake 150C	1000hrs	3/75/0					3/231/0
MQ	Manufacturability qualification	TI internal procedure	Pass	Pass	Pass	Pass	Pass	Pass

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable
- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours
- The following are equivalent HTSL options based on an activation energy of $0.7 \mathrm{eV}$: $150 \mathrm{C}/1 \mathrm{k}$ Hours, and $170 \mathrm{C}/420$ Hours
- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles Quality and Environmental data is available at Tl's external Web site: http://www.ti.com/

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

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